

Acknowledgments

This work was funded by the National Natural Science Foundation of China (Grant Nos. 51475191 and 51405172), the National Instrument Development Specific Project of China (Grant No. 2011YQ160002), and the Program for Changjiang Scholars and Innovative Research Team in University of China. The authors would like to thank the facility support of the Center for Nanoscale Characterization and Devices, Wuhan National Laboratory for Optoelectronics (WNLO) (Wuhan, China).